Abstracts

Distributed Analysis of Submicron-MESFET Noise-Properties

W. Heinrich. "Distributed Analysis of Submicron-MESFET Noise-Properties." 1988 MTT-S International Microwave Symposium Digest 88.1 (1988 Vol. I [MWSYM]): 327-330.

A distributed MESFET noise-analysis is presented. Its results are used to determine the validity range of common lumped-element models. We found that in well-designed submicron LN-MESFETs distributed effects may be neglected. Practical gate-width design-values are given.

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